Materials Characterization Laboratory

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Materials Science and Engineering Department



- The Materials Characterization Lab is the only general user facility for research in the Materials Science and Engineering Department.
- We house several pieces of equipment and offer a variety of characterization capabilities for many types of material systems.
- The facility caters to researchers with many scientific backgrounds. We welcome users of a broad spectrum, ranging from undergraduate students to professional engineers and scientists.
- The facility is staffed by students with oversight from Professors Taylor Sparks and Mike Scarpulla.



Spectroscopy Equipment

- Powder X-ray Diffraction
 - Phase Identification
 - Reitveld Refinement
 - Data Base Search
 - Table Top and Full Sized Units
- Fourier Transform Infrared Spectroscopy
 - Spectroscopy in the Mid IR range
 - Absorbance and Transmittance Measurements
 - Attenuated Total Reflectance Accessory
- Ultraviolet-Visable-Near-Infrared Spectroscopy
 - Absorbance, Transmittance, and Reflectance Measurements in the UV-Visible-NIR Range
- Energy Dispersive Spectroscopy
 - Equipped with SEM
 - Elemental Composition Analysis



Microscopy Equipment

- Optical Microscopes
 - Metallographic Analysis
 - Camera Tools
 - Quantitative Phase Measurements
- Scanning Electron Microscope
 - Grain Size Analysis
 - Morphology
 - Sub-Micron Resolution
- Atomic Force Microscope
 - Nanoscale Surface Topography





Thermal and Mechanical Testing Equipment

- Instron Tensile and Mechanical Testing
 - Stress, Strain, Creep, Measurements
 - Tensile, Compression, Flexure Testing
 - Loads up to 50kN
- Differential Scanning Calorimeter
 - Phase Transition Measurements
 - Heat Capacity
 - Measurements from -250-600 Degrees C
- Dilatometer
 - Thermal Expansion up to 1200 Degrees C





Other Tools

- Sample Preparation:
 - Diamond Saw
 - Hot Press Mounting
 - Automatic and Manual Polishing and Grinding Equipment
 - Consumables for Metal and
 Ceramic Microscopy Preparation
 - Conductive Gold Sputtering
- Surface Area and Pore Analyzer
 - Surface Area and Pore size Analyzer using B.E.T. Method



